

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-1363	SERIAL NO. 09/512,968
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.	
					FILING DATE February 24, 2000	PRIORITY GROUP 2829
U.S. PATENT DOCUMENTS						
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
✓	AA	5,703,287	12/1997	Treutler et al.	_____	_____
↓	AB	5,945,834	8/1999	Nakata et al.	_____	_____
↓	AC	5,478,242	12/1995	Walker et al.	_____	_____
↓	AD	5,830,372	11/1998	Hierold	_____	_____
↓	AE					
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)						
AF						
AG						
AH						
AI						
AJ						
AK						
AL						
EXAMINER <i>anh Nguyen</i>				DATE CONSIDERED <i>06/02/05</i>		
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M22-1363	SERIAL NO. 09512,988
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U.S. PATENT DOCUMENTS						
Examiner Initial	Class	Document Number	Date	Name	Class	Subclass
VN	AA	8,633,852	10/21/2003	Selwa	—	—
VN	AB	8,708,878	3/23/2004	Akram et al.	—	—
VV	AQ	6,643,701	11/11/2000	Ota et al.	—	—
	AD					
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					
EXAMINER <i>mh Nguyen</i>				DATE CONSIDERED <i>06/02/05</i>		
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